

# 3D Thin Film Metrology Workshop

**THURSDAY, 26 JUNE 2025**

Parnas Hotel  
Jeju Island, South Korea



## ABOUT WORKSHOP

Join experts, researchers, and industry leaders for a one-day workshop on thin film metrology in high aspect ratio (HAR) structures, featuring the latest in ALD applications, conformality analysis, and advanced measurement techniques.

## Why Attend?

- Discover the latest tools and methodologies for 3D thin film metrology.
- Learn from top researchers and engineers in the field.
- Engage in hands-on training and discussions.

## Registration Details

- Fee: €250 (includes lunch, coffee, refreshment, and all workshop materials)
- Register now from [here](#)

**Spaces are limited. Secure your spot today!**

# Program at a Glance

Time	Activity
09:30–10:30	Get-together (Coffee and light snacks)
10:30–10:45	Welcome & Opening Remarks
10:45–11:30	Keynote Presentation: Advanced solutions for thin film process control
11:30–12:30	Hands-on Session with PillarHall test chip
12:30–14:00	Lunch & Business break
14:00–14:45	Presentation: Challenges and best practices in conformality measurement in HAR structures
14:45–15:00	Coffee break
15:00–16:00	Round table Discussion: <i>Challenges in Sub-Angstrom Measurements</i> + Q&A
16:00–19:00	Refreshment

## Additional Information:

- Limited seats available – early registration is recommended.
- Official language: English (Korean interpretation available).



**CHIPMETRICS**

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Chipmetrics

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